

A Charge-Sensitive Amplifier Associated with APD or PMT for Positron Emission Tomography Scanners

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Outline

1. PET scanners and electronic architecture
2. Charge Sensitive Amplifier design
3. Noise considerations
4. Layout design
5. Test set up and measurements
6. Conclusion

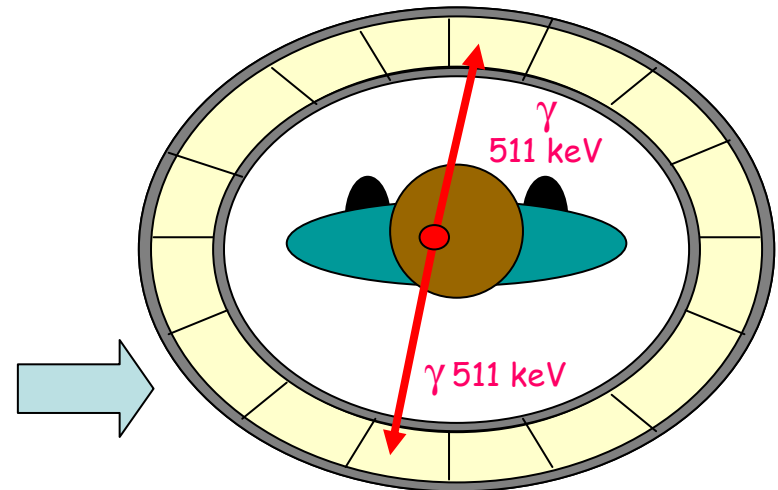
1 : PET Scanners Concept

Sensitive instruments for biomedical imaging :

- Brain studies
- Cardiac imaging
- Cancer diagnosis and therapy

PET scanners operation :

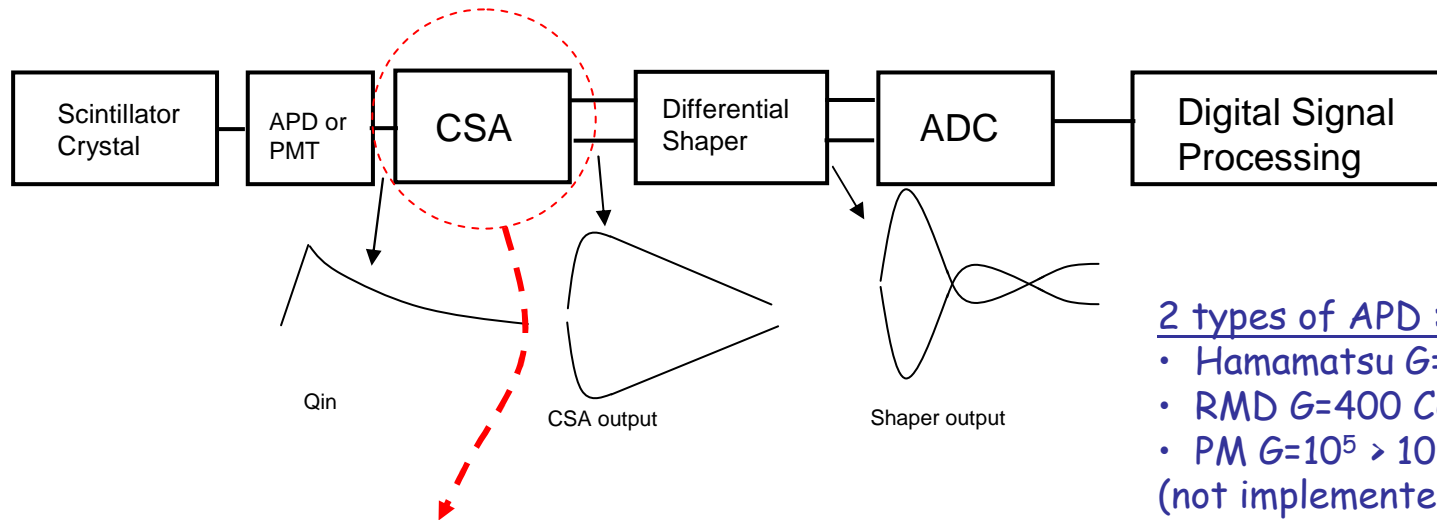
- Detection in coincidence of 511 KeV Photon pair



Main ideas :

- o Use LHC (CERN) electronics concepts
- o Dead time reduction \ll 1ns
- o Spatial resolution \sim 1mm
- o Improvements of PET performances

1 : Electronic Architecture



2 types of APD :

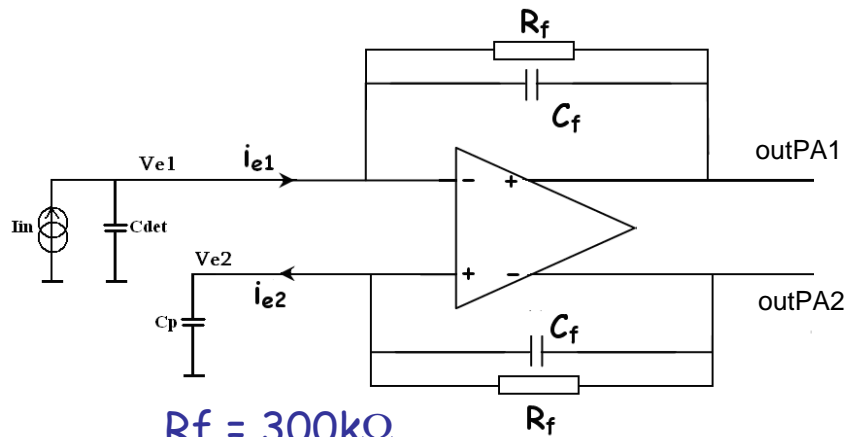
- Hamamatsu $G=200$ $C_d=80\text{pF}$ $Q_{\text{max}} = 200\text{fC}$
- RMD $G=400$ $C_d=50\text{pF}$ $Q_{\text{max}} = 500\text{fC}$
- PM $G=10^5 > 10^6$ $C_d=10\text{pF}$ $Q_{\text{max}}=10\text{pC}$
(not implemented in this design)

Main difficulty :

- High value of C_d
- Low Q_{max}

Noise :

- Shaper time constant = 20ns
- ENC = 3000 e- (With APD stimulus)



$R_f = 300\text{k}\Omega$
 $C_f = 1\text{pF}$

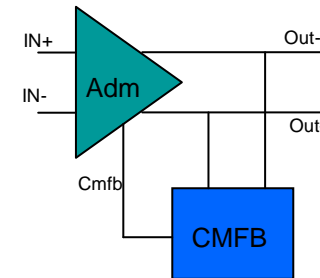
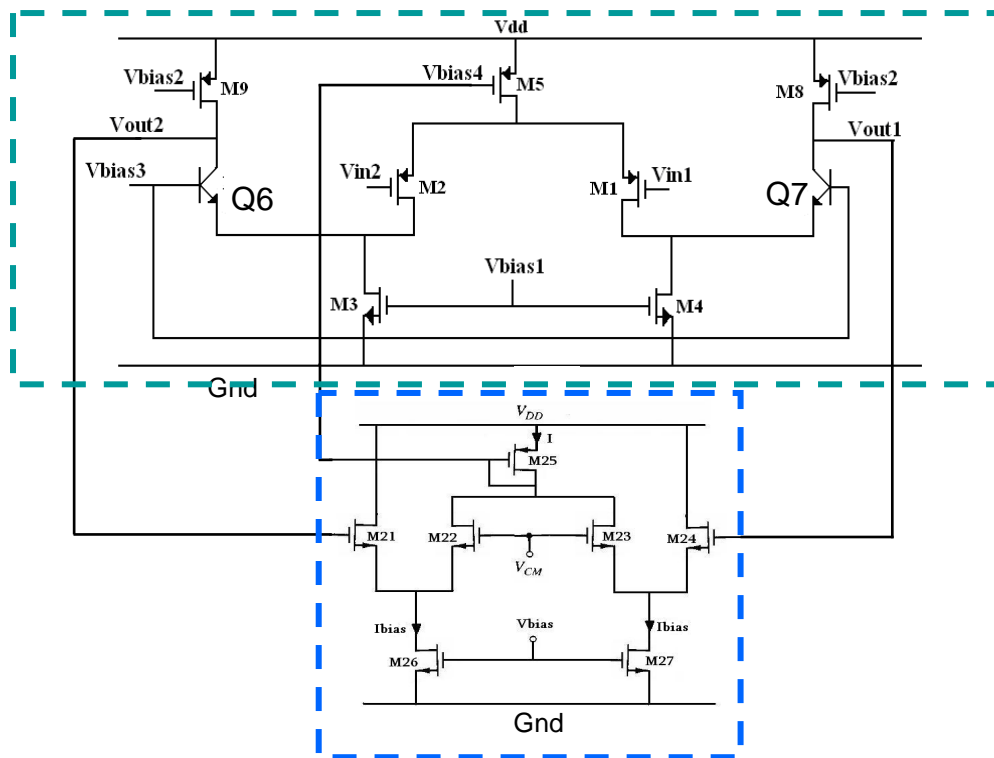
Differential mode :

- Shaper and ADC architecture
- APD or PM

2 : Charge Sensitive Amplifier Design

CSA is made with a fully differential amplifier = Adm + CMFB

Technology : AMS 0.35 μ m BiCMOS SiGE S35D4M5
4 metal, 2 poly, high resistive poly

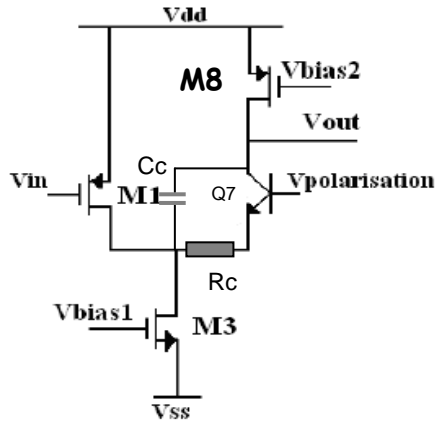


CMFB acts as :

- Control of common mode output voltage
- In single input mode : reduce residual voltage

2 : Charge Sensitive Amplifier Design

Half Adm part



$$A_0 \approx -\frac{g_{m1}}{g_{ds8}}$$

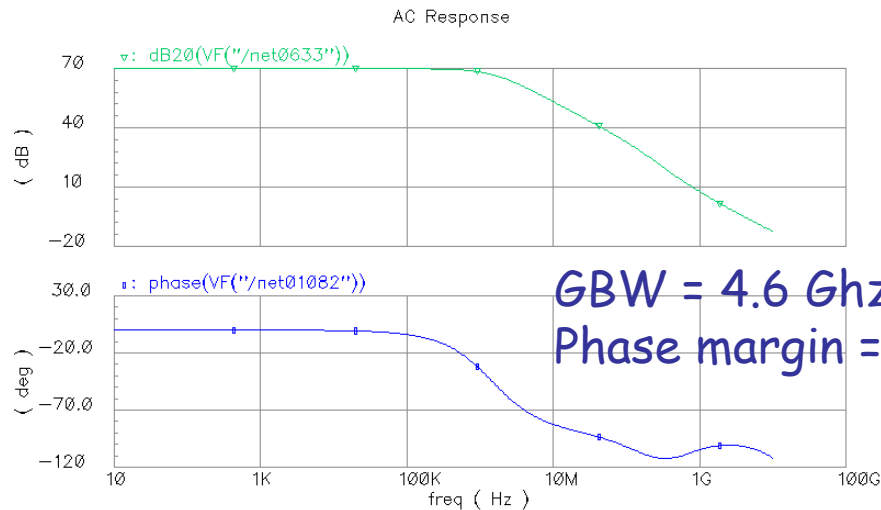
$$f_c = \frac{g_{ds8}}{2\pi C_{out}}$$

$$g_{ds1} \leq \frac{1}{R_c} \leq g_{m7}$$

CMFB part

$$P_{nd} = \frac{g_{m25}}{C_{gs5} + C_{gs25}}$$

$$I_{ds25}/I_{ds5} \sim 1$$



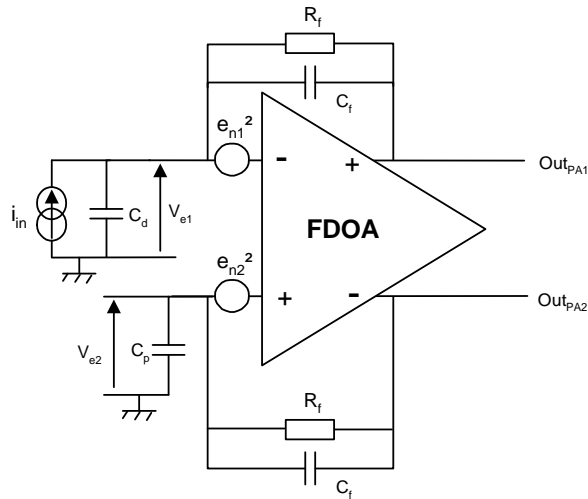
CSA input characteristics

$$\tau_{csa} = \frac{C_d}{2\pi \cdot GBW \cdot C_f} = C_d \cdot R_{in}$$

$$R_{in} = \frac{C_{out}}{g_{m1} \cdot C_f}$$

3 : Noise considerations

(Noise is a Key issue for this design)



$$S_n = \frac{8 kT}{3 g_{m1}} + \frac{K_f}{C_{ox}^2 W L f}$$

$C_f \ll C_p$ and $C_f \ll C_d$

$$\Delta V_{out}(\omega) = \frac{2A_{dm} [(v_1 - v_2) - V_{out,cm}(\beta_1 - \beta_2)]}{2 + A_{dm}(\beta_1 + \beta_2)}$$

$$\beta_1 = \frac{\frac{1}{j\omega C_p}}{\frac{1}{j\omega C_p} + \frac{R_f}{1 + j\omega R_f C_f}} \sim \frac{1 + j\omega C_f R_f}{1 + j\omega C_p R_f} \quad \beta_2 = \frac{\frac{1}{j\omega C_d}}{\frac{1}{j\omega C_d} + \frac{R_f}{1 + j\omega R_f C_f}} \sim \frac{1 + j\omega C_f R_f}{1 + j\omega C_d R_f}$$

$$H_n(\omega) \approx \frac{\Delta V_{out}}{V_{1,2}} \approx \frac{2}{\beta_1 + \beta_2} \approx \frac{2}{\frac{1 + j\omega C_f R_f}{1 + j\omega C_d R_f} + \frac{1 + j\omega C_f R_f}{1 + j\omega C_p R_f}} \approx \frac{2}{C_f \left(\frac{1}{C_d} + \frac{1}{C_p} \right)} \approx \frac{2C_d}{C_f} \quad \text{Noise Gain} \quad H_n(\omega) \approx \frac{C_d}{C_f}$$

$$v_{noise}^2 \approx \int_0^\infty 2S_n |H_n(f)|^2 \frac{G^2 (2\pi f \tau_s)^2}{[1 + (2\pi f \tau_s)^2]^2} df \approx \frac{G^2}{\tau_s} \left(\frac{2}{C_f \left(\frac{1}{C_d} + \frac{1}{C_p} \right)} \right)^2 \frac{2kT}{3g_{m1}} \approx \frac{G^2}{\tau_s} \left(\frac{2C_d}{C_f} \right)^2 \frac{2kT}{3g_{m1}}$$

3 : Noise considerations

$$V_{out, shaper}(\tau_s) = 2 \cdot \frac{qG}{e.C_f}$$

In differential mode

$$ENC \approx \frac{eC_d}{q} \sqrt{\frac{2kT}{3\tau_s g_{m1}}}$$

Serial noise only

$$ENC \approx \frac{eC_d}{q} \sqrt{\frac{kT}{\tau_s} \left(\frac{2}{3g_{m1}} + r_{poly} \right)}$$

Including access gate serial resistor r_{poly}

PMOS input Optimization :

- Increase Gm (100 mA/V @ Id 10 mA and w/l =5000/0.35)
- Minimize WL to minimize Cgs input transistor capacitance
- Minimize in layout access gate serial resistor

3 : Noise considerations

Differential output

$$ENC \approx \frac{eC_d}{q} \sqrt{\frac{2kT}{3\tau_s g_{m1}}}$$

Single ended output

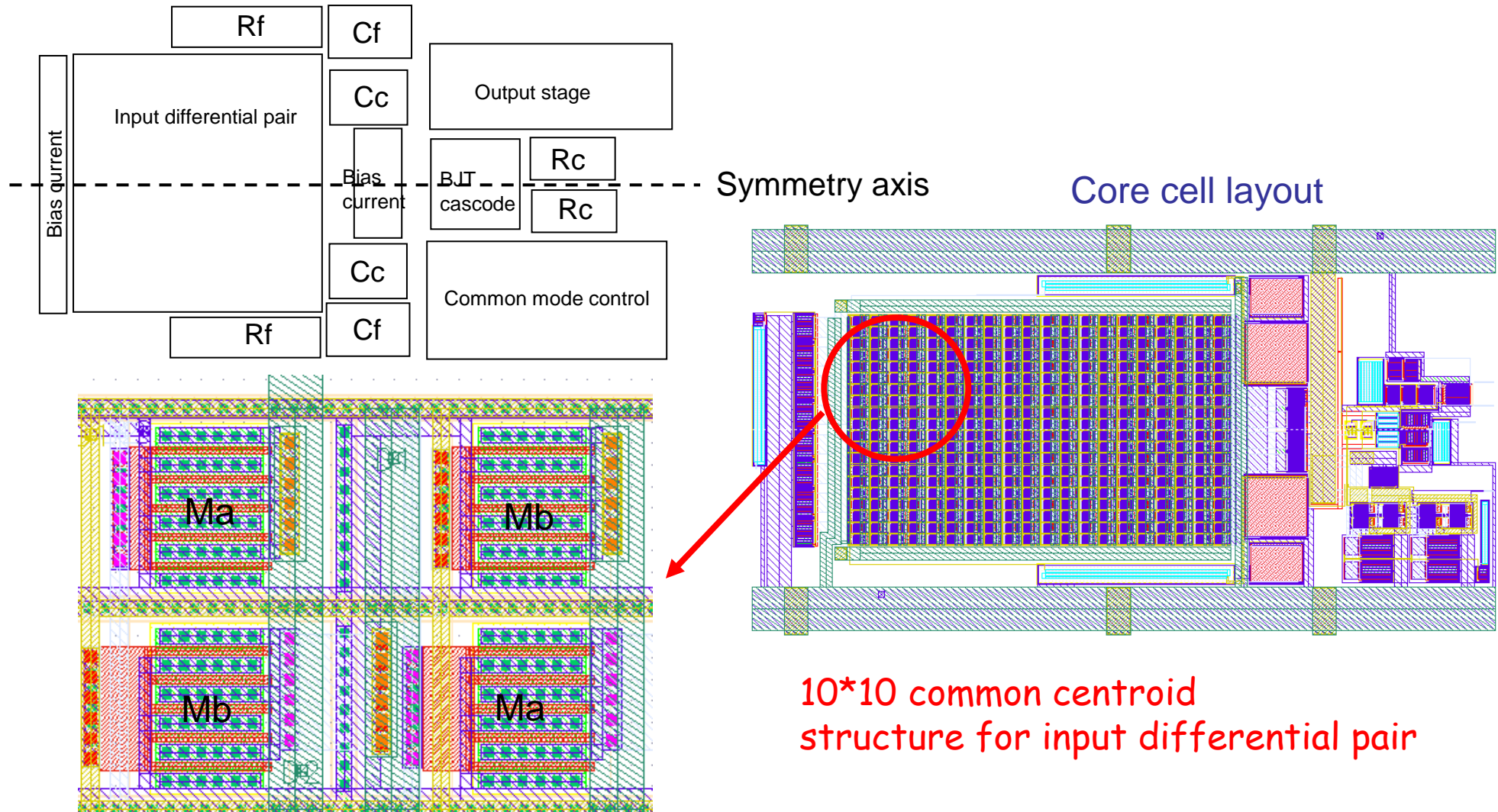
$$ENC \approx \frac{eC_d}{q} \sqrt{\frac{kT}{3\tau_s g_{m1}}}$$



$*\sqrt{2}$

- *ENC increase by a factor sqrt(2)*
- Adaptation to either PMT or APD
- Less sensitive to coupling (common mode)

4 : Layout Design

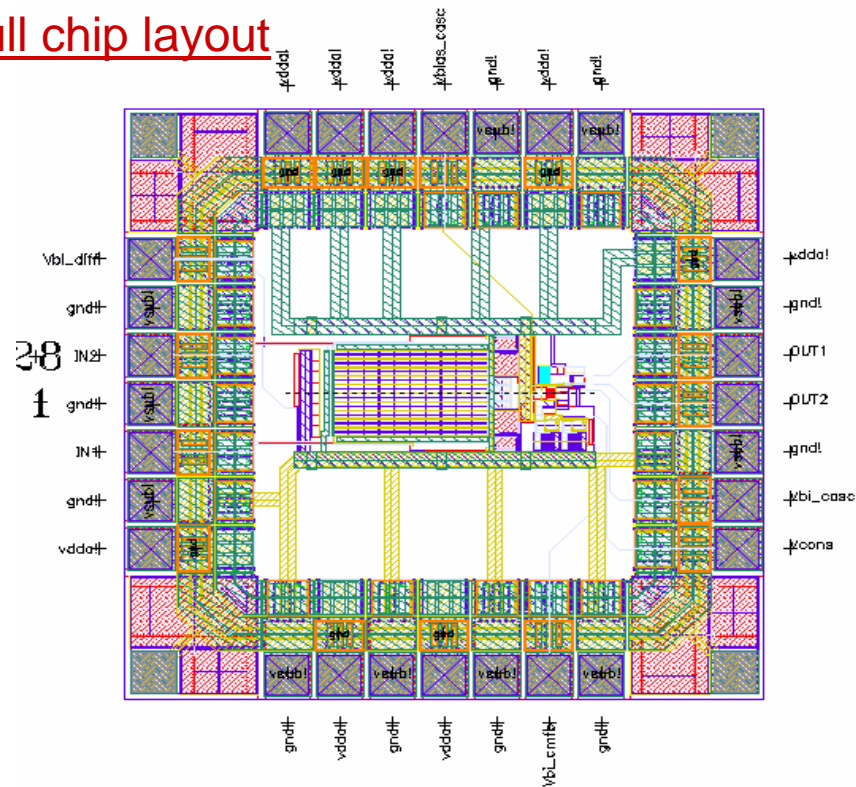


Special thanks to E. Bechetoille for his help

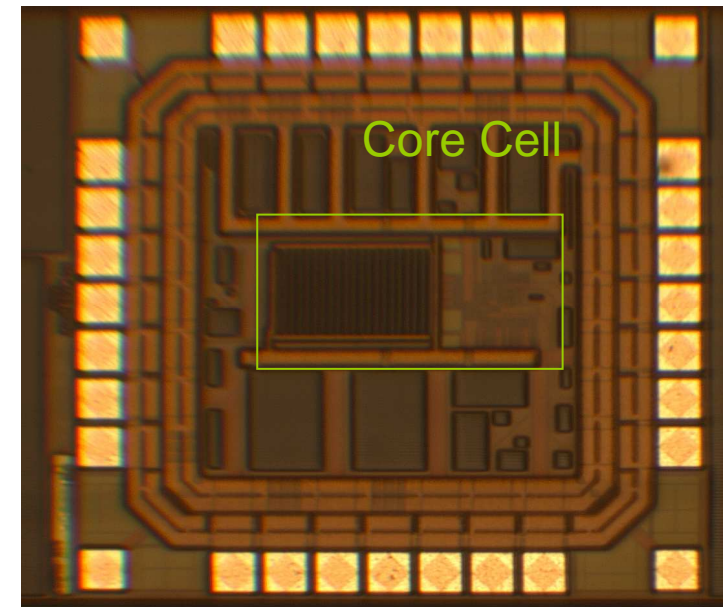
4 : Layout Design

- Chip was submitted in MPW in November 2008 through CMP
- Return in February 2009 and fully tested
- 28 pins JLCC ceramic package

Full chip layout

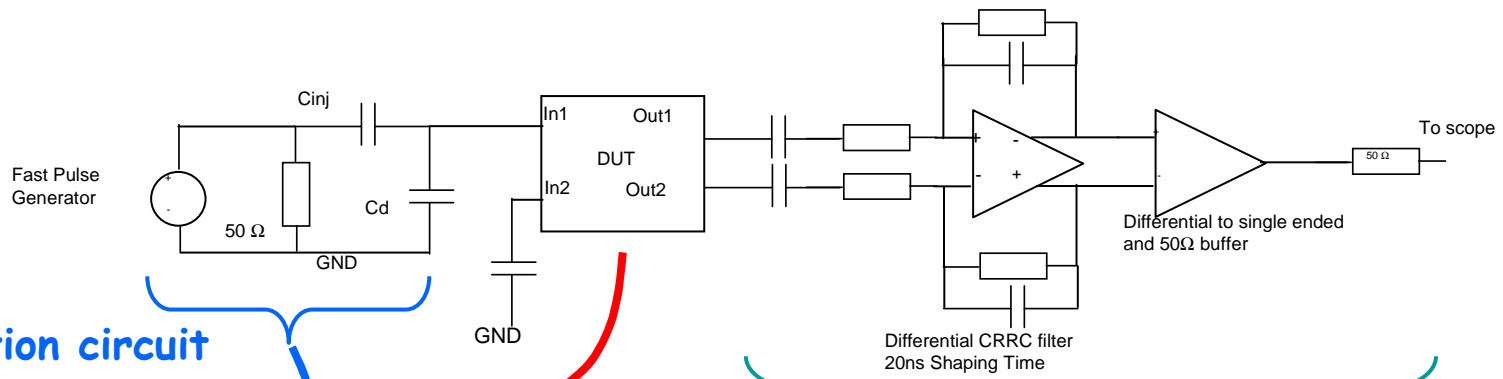


Photography



Core cell area = 0.2 mm²

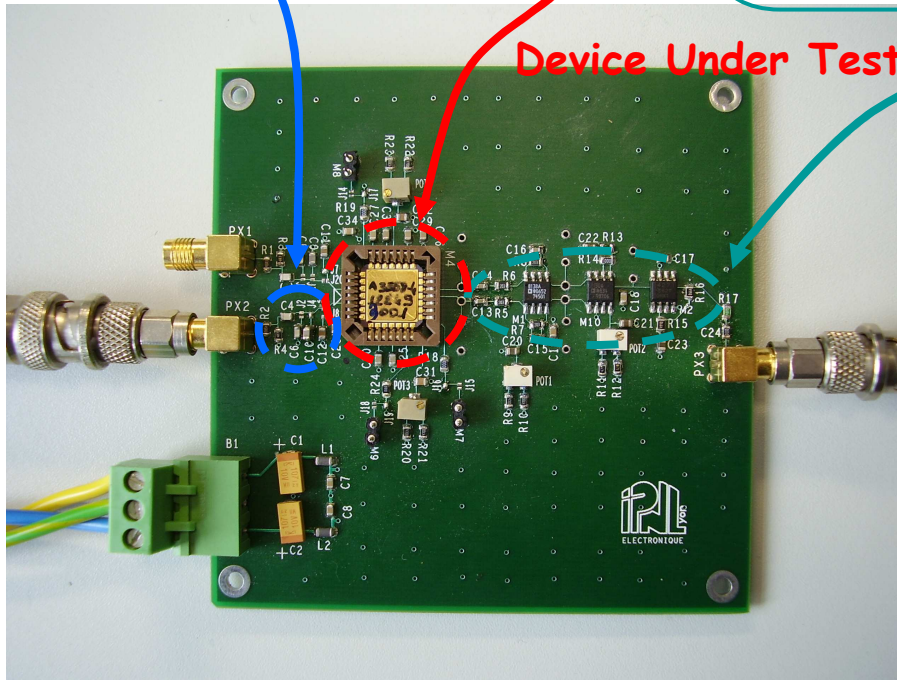
5 : Test setup



Charge injection circuit

Device Under Test

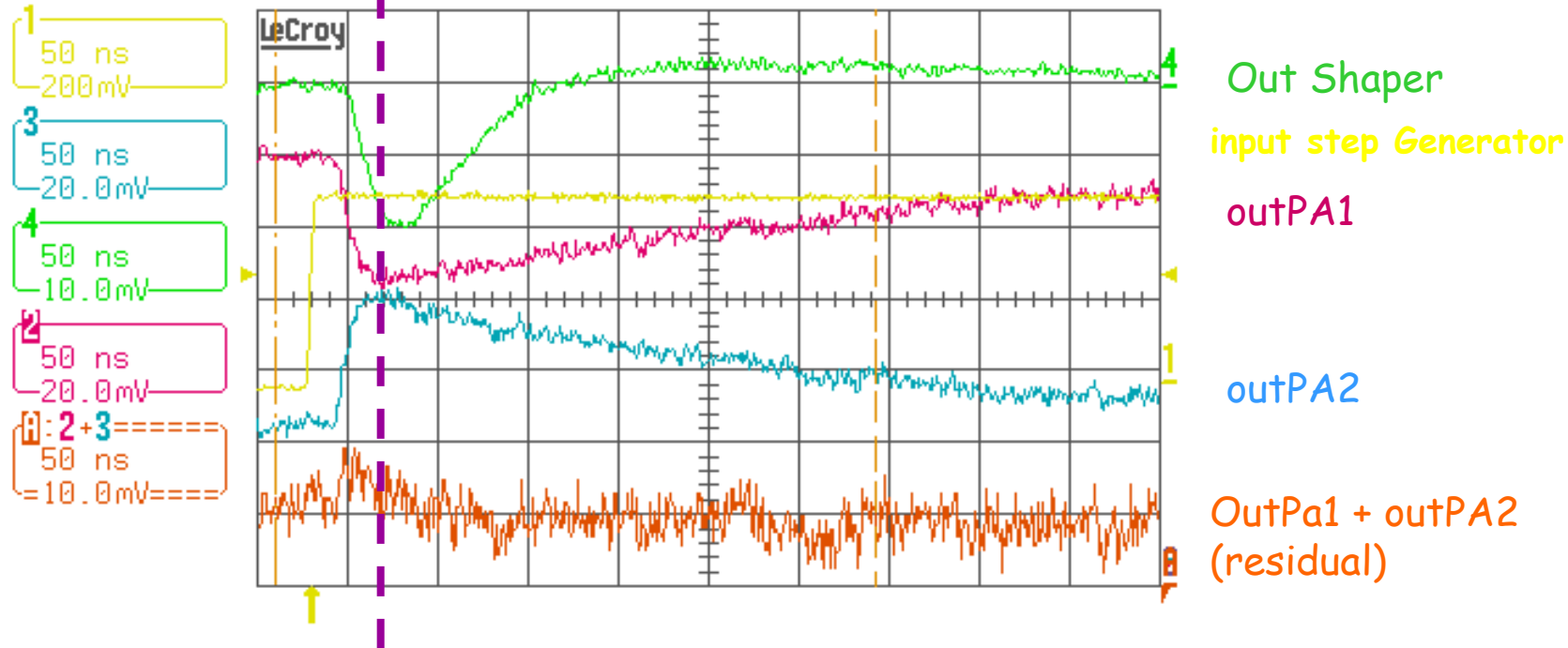
Readout circuit



5 : Results

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$Q_{in} = 50\text{fC}$ (pulsed mode)



Differential output voltage = 80 mV

Peaking Time = 25 ns (CSA)

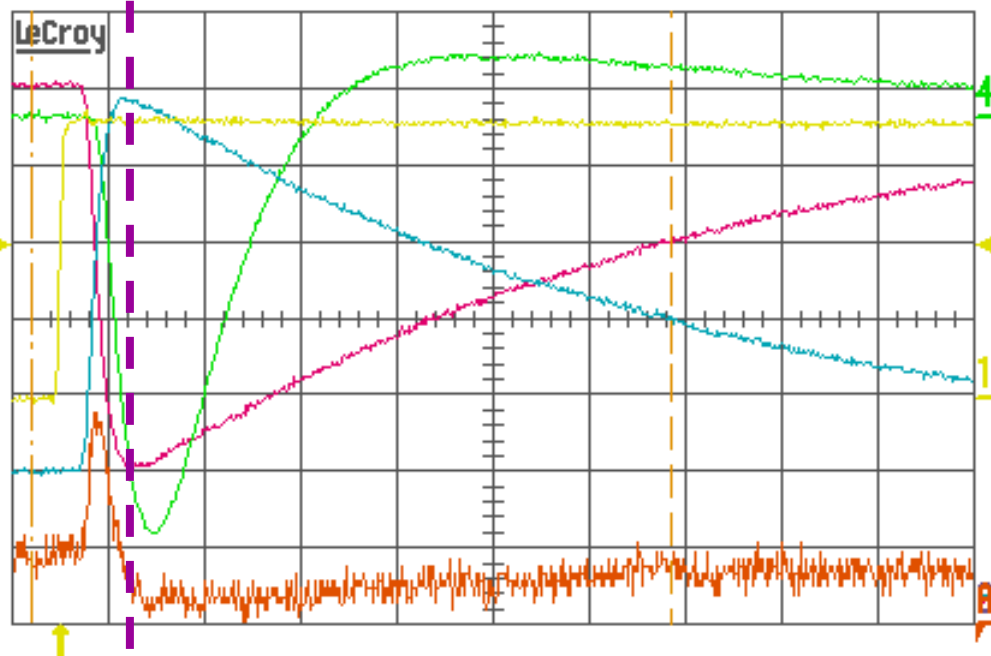
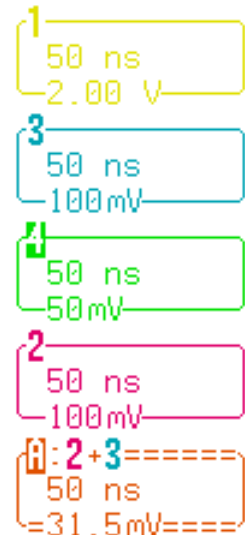
Residual voltage = 8 mV

Conversion gain = 1.44 mV/fC

5 : Results

$Q_{in} = 700\text{fC}$ (pulsed mode)

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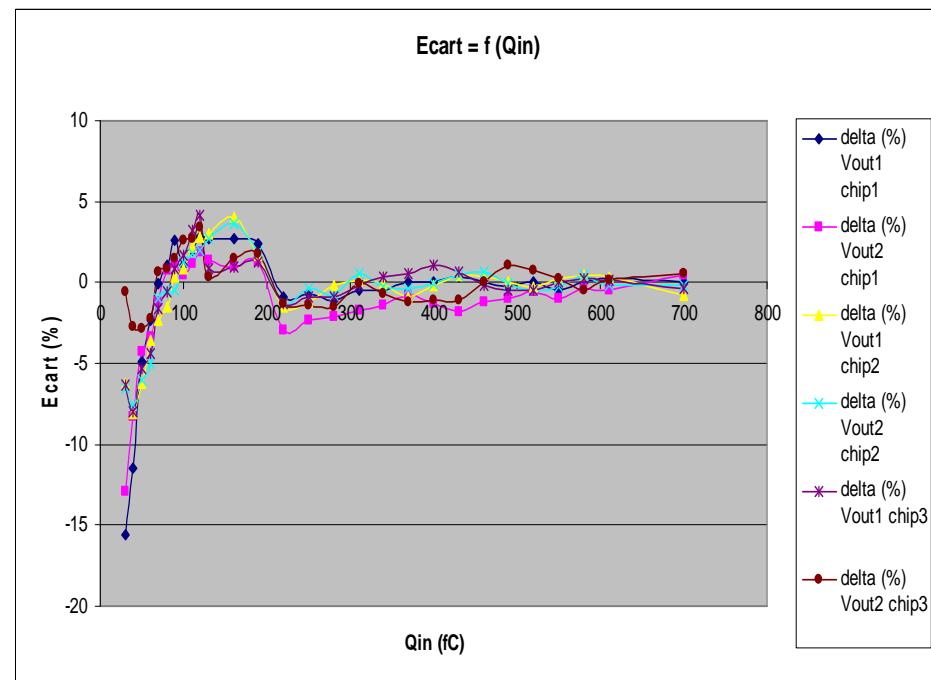
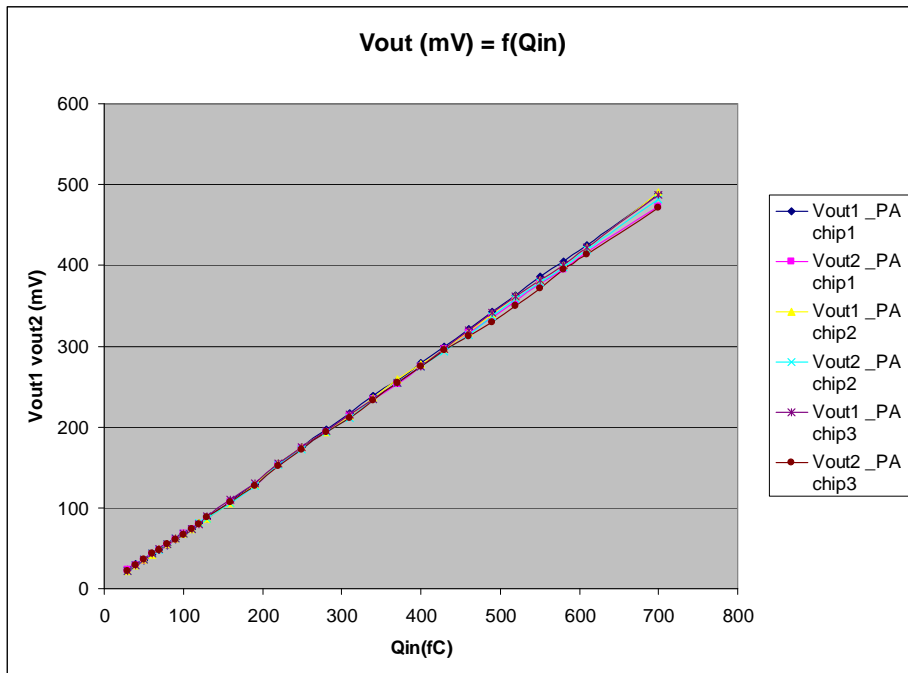
Out Shaper
input step Generator
outPA1
outPA2
OutPa1 + outPA2
(residual)

Differential output voltage = 980 mV
Peaking Time = 26 ns
Residual voltage = 50 mV
Conversion gain = 1.4 mV/fC

5 : Results

outPA1, outPA2, 3 chips fully tested from 50fC to 700fC in pulsed mode

Nonlinearity

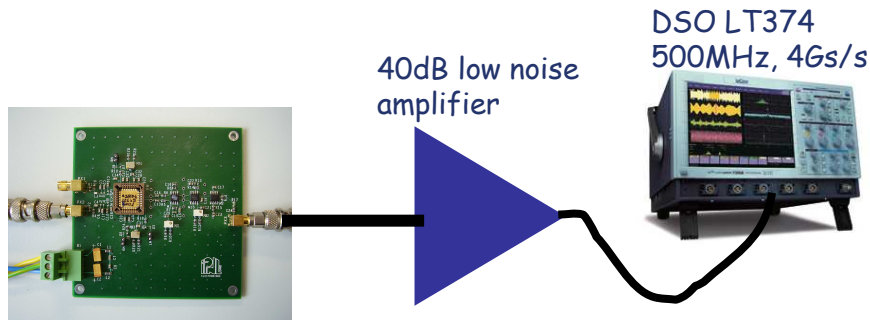


OutPA1,2 slope = 0.7 mV/fC
 \Rightarrow 1.4 mV/fC in differential mode



NL estimated by : $(\text{measure} - \text{linear fit}) / \text{measure}$
 At low injection NL is dominated by instruments accuracy
 NL is less than $\pm 2\%$ for $Q_{in} > 100\text{fC}$

5 : Results



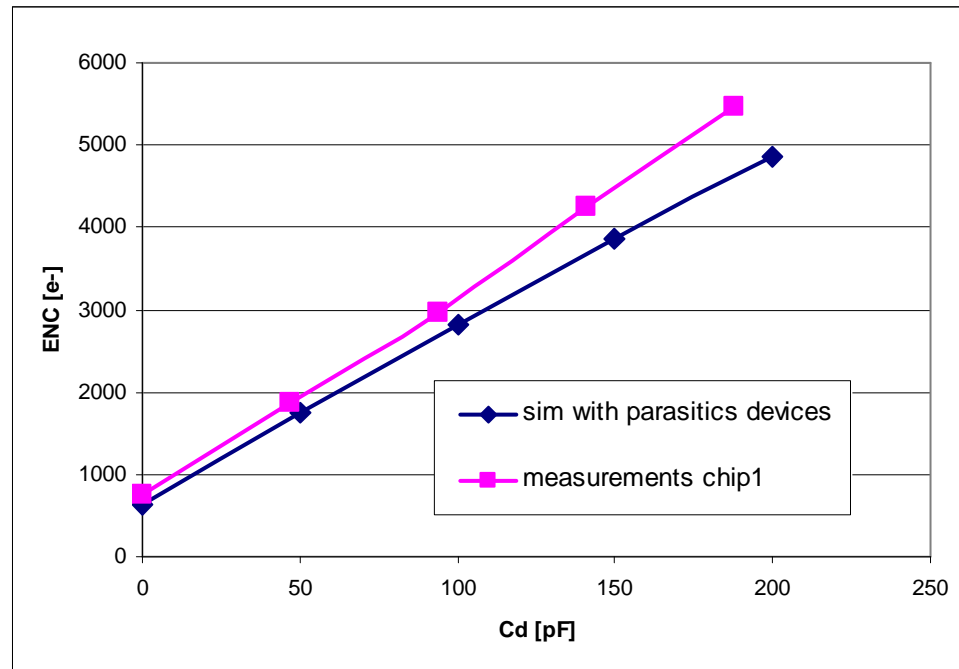
Noise Results :

$$ENC = 2000 e^-$$

$$Cd = 50pF$$

G_{conv} : estimated with pulsed stimulus ($\sim 40 mV/fC$)

Shaper time constant : 20ns



$$ENC_{meas} = 692 e^- + 25 e^-/pF$$

$$ENC_{sim} = 670 e^- + 21 e^-/pF$$

6 : Conclusion

- o Proceeding conference MIPRO (Croatia may 2009)
- o Paper submitted in MIM-A

We designed a CSA in differential mode (APD, PM) which is adapted to the post processing (differential shaper and ADC)

Results are (3 chips were measured) :

- ✓ Rise time 26ns for pulsed stimulus
- ✓ Rise time ~ 110ns for APD like stimulus
- ✓ Noise 2000 e- @ Cd=50pF, pulsed stimulus, 20ns shaper time constant
- ✓ Noise 3200 e- @ Cd=50pF, APD stimulus, 20ns shaper time constant
- ✓ Dynamic range 700fC
- ✓ Conversion gain 1.34mV/fC
- ✓ Area = 0.195 mm² not including pad ring
- ✓ Power supply = 136 mW @ 3.5V